WED3EL7216S, DDR SRAM, 2.5v CORE/ 2.5V IO Advanced*

FEATURES

- Core Supply Voltage = 2.5v +/-0.2v
- IO Supply Voltage = 2.5v +/- 0.2v
- Bidirectional data strobe (DQS)
- Internal, pipelined, double data rate architecture
- Differential Clock Inputs
- Positive edge; Command execution
- DLL for alignment of DQ and DQS transitions
- Four internal banks for concurrent operation
- Data Mask (DM) for masking write data
- Programmable IOL/IOH
- Programmable Burst length: 2,4, or 8
- Auto Precharge option
- Auto Refresh and Self Refresh Modes

GENERAL DESCRIPTION

The White Electronic Designs DDR SDRAM (x72/80) is a synchronous dynamic random-access memory supporting data transfer on each of the clock edges within a single cycle, and is configured internally as a quad bank architecture which supports concurrent operations.

The double data rate (DDR) architecture is referenced to as a 2n-pre-fetch architecture with an interface designed to transfer two data words per clock cycle. A single Read or Write access consists of a single 2n-bit wide, one clock cycle data transfer at the internal DRAM core and two corresponding n-bit wide, one half clock cycle data transfers at the I/O pins.

The WED3EL7216S devices contain differential clock inputs; the crossing of CK going through its voltage transition to a high true, and CK\ going through its voltage transition to a low true references a positive edge. Commands as well as Address(s) and Control(s) are registered on positive edges, Data is registered on both edges as well as Output Data is referenced on both edges of the Clock.

Read and Write accesses to the DDR SDRAM are burst oriented; accesses start at a selected location and continue

for a programmed number of locations, as defined by the programmable burst command.

INITIALIZATION

DDR SDRAMs must be initialized via properly powering up. Operation and use of this device outside of established procedure(s) may result in undefined operation. Power must be first applied to Vcc and VccQ simultaneously and then Vref (and System Vtt) must be applied after VccQ in order to avoid device latch-up. Vref may be applied any time after VccQ but is normally expected at coincidence with Vtt. Except for CKE (clock enable) inputs are not recognized as valid until after Vref is applied. CKE is an SSTL 2 input but will detect an LVCMOS Low level after Vcc is applied. Maintaining an LVCOMOS Low level on CLE during power-up is required to ensure that the DQ and DQS outputs will be in the HIGH-Z state where they will remain until driven in a normal READ operation. Once the POWER SUPPLY, and REF-ERENCE VOLTAGE is STABLE, the DDR SDRAM device requires 200us delay prior to execution of a COMMAND sequence. Once the 200us delay requirement has been meet, a DESELECT or NOP command should be applied, and CKE should be brought HIGH. Following the NOP command, a PRECHARGE ALL command should be applied. Next a LOAD MODE REGISTER command is to be issued for the extended mode register (enabling the DLL) followed by another LOAD MODE REGISTER command to be issued to reset the DLL and program the operating parameters. Two hundred (200) clock cycles are required between the DLL reset and any READ command. A PRECHARGE ALL command should then be applied, placing the device in the all banks idle state.

Once in the Idle state, two AUTO REFRESH cycles must be performed. Additionally, a LOAD MODE REGISTER command for the mode register with the reset DLL bit deactivated is required. Following these requirements, the DDR SDRAM is ready for NORMAL OPERATION.

PROGRAMMABLE IOH/IOL

The normal full drive strength for all outputs are specified to be SSTL class 2. The WED3EL7216 supports an option for reduced drive. This option is intended for the support of the lighter load and or point-to-point environments. The command and placement of this device into reduced drive mode will place the output drive at $\sim 54\%$ of the SSTL-2.

DESELECT

The DESELECT command prevents new commands from being executed by the WED3EL7216S devices.

NO OPERATION (NOP)

The NOP command is used to instruct the selected DDR SDRAM device to perform idle or wait states. During these states, the DDR SDRAM device is unable to register new commands, operations already in progress are not affected.

LOAD MODE REGISTER

The MODE REGISTERS are loaded via inputs A0-A11. The LOAD MODE REGISTER command can only be issued when all DDR SDRAM internal banks are idle.

ACTIVE

The ACTIVE command is used to open (or activate) a row in a particular bank for a subsequent access. The value on the BAO, BA1 inputs selects the bank, ant the address provided on inputs AO-A11 selects the row. The row remains active for accesses until a PRECHARGE command is issued. A PRECHARGE command must be issued before opening a different row in the same bank.

READ

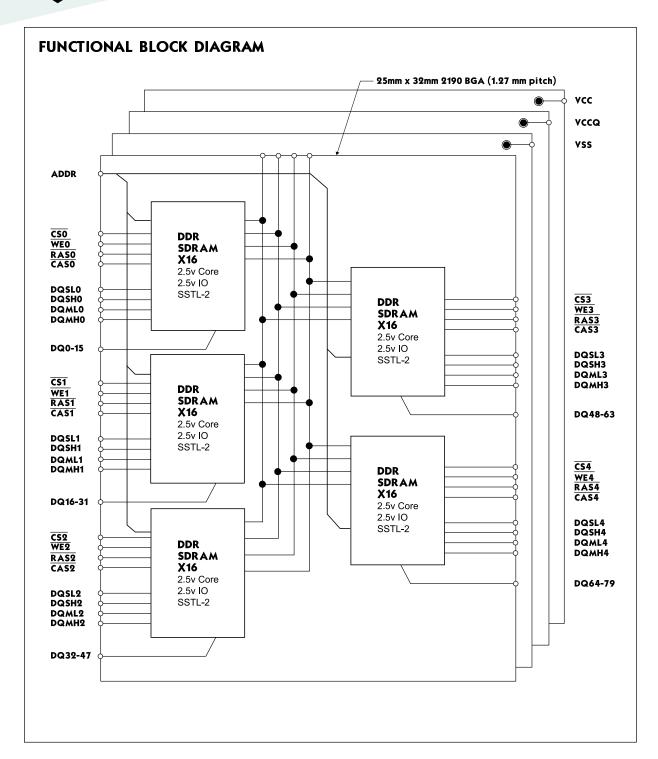
The READ command is used to initiate a BURST READ access to an active row. The value on the BAO, BA1 inputs selects the bank, and the address provided on inputs AO-Ax. Addressed location of the array will drive its contents onto the DQ's or the device.

WRITE

The WRITE command is used to initiate a burst write. Input data appearing on the DQ's will be written into the address location of the array.

PRECHARGE

The PRECHARGE command is used to deactivate the open row in a particular bank or the open row in all banks. The bank(s) will be available for a subsequent row access a specified time (tRP) after the PRECHARGE command is issued.



PIN CONFIGURATION

1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16

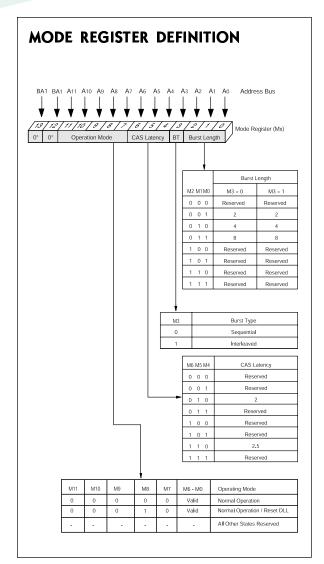
Α (DQ0) (DQ14) (DQ15) (Vss) (Vss) **A**9 A10 (A11) **A**8 (VccQ) (VccQ) (DQ16) (DQ17) (DQ31) Vss В (DQ2) (DQ12) (DQ13) (v_{ss}) (vss) Ao) Α7 A6 Α1 Vcc (vcc) (DQ18) (DQ19) (DQ29) (DQ30) C (DQ3) (DQ4) (DQ10) (DQ11) (Vcc) (Vcc **A**2 **A**5 A4 Аз Vss (Vss (DQ20) (DQ21) (DQ27) (DQ28) (DQ_6) (DQ_5) (DQ8) (DNU (DNU) (DNU) Vss (DQ22) (DQ23) (DQ26) (DQ25) D (DQ9) (VccQ) (Vcca (A12/NG) Vss Ε (DQML0) Vcc (DQMH0) (рознз) (DQSH0) (BAo (BA1) (DQSL1) (DQSH1) (VREF) (DQML1) Vss) NC (DQ24 F $(\overline{WE0})$ (WE1) vss) (CLK1 (Vcc) (CLK₀) (DQSL3) (RAS1) (DQMH1) G (RASO) (Vcc) (CKE0) CS1 Vss (CLK) (CKE1) (Vss) (Vcc Vss Vss) (Vcc (VccQ) Vss (VccQ) Η (v_{cc}) Vss (Vss J (vss) (VccQ) Vss) (VccQ) (Vcc (CKE3) (Vcc) $(\overline{CS3})$ DQSL4 (CKE2) (vss) (RAS2) (CS2 (WE2) NC (CLK3) (Vcc) (CAS3) (RAS3) (CLK2) vss) (CAS2 (DQ56) (DQMH3) Vcc (WE3) (DQML3) (CKE4) (DQMH4) (CAS4) (WE4) (RAS4) $(\overline{CS4})$ (DQMH2) Vss) (DQ39) Μ (DQ57) (DQ58) (DQ54) (DQ73) (DQ40) (DQ37) (DQ38) (DQ55) (DQSH4) (DQ70) (pash2) (DQ41) Ν (CLK4) (DQ71) (DQ59) (DQ53) (DQ52) (DQ75) (DQ68) (DQ42) (DQ36) (DQ35) Ρ (DQ60) Vss (Vss (DQ74) (DQ69) Vcc (Vcc (DQ43) (DQ51) (DQ77) (DQ44) (DQ34) (DQ33) (DQ62) (DQ61) (DQ50) Vcc Vcc (DQ76) (DQ67) (DQ66) Vss Vss (DQ45) R (DQ64) (DQ63) (DQ49) (DQ79) (DQ65) (DQ47) (DQ46) (DQ32) Т

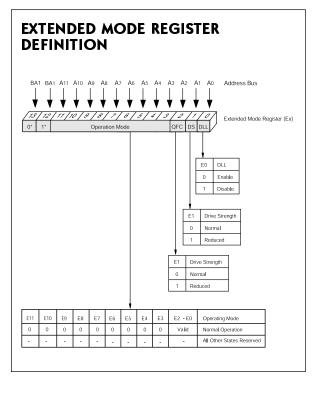
PIN DESCRIPTIONS

BGA LOCATIONS	SYMBOL	DESCRIPTION
F4, F16, G5, G15, K1, K12, L2, L13, N6, M8	CKx, CKx\	Clock: CKx and CKx\ are differential clock inputs. All address and cont rol input signals are sampled on t he crossing of t he posit ive edge of CKx and negat ive edge of CKx\. Out put dat a (DQ's and DQS) is referenced to the crossings of the differential clock inputs
G4, G16, K2, K13 M6	CKEx	Clock Enable: CKE cont rols t he clock input s. CKE high enables, CKE Low disables the clock input pins. Driving CKE Low pro-vides PRECHARGE POWER-DOWN and SELF REFRESH operations, or ACTIVE POWER-DOWN. CKE is synchronous for POWER-DOWN ent ry and exit, and for SELF REFRESH ent ry CKE is Asynchronous for SELF REFRESH exit and for disabling the outputs. CKE must be maintained HIGH throughout read and writ e accesses. Input buffers are disabled during POWER-DOWN Input buffers are disabled during SELF REFRESH. CKE is an SSTL-2 input but will det ect an LVCMOS LOW level aft er VCC is applied
G1, G13, K4, K16 M12	CSx\	Chip Select: CSx\ enagles t he COMMAND regist er(s) of each of t he five (5) cont ained words. All commands are masked when CSx\ is registered HIGH. CSx\ provides for external bank selection on systems with multiple banks. CSx\ is considered part of the COMMAND CODE.
F4, F16, G5, G15, K1, K12, L2, L13, N7, M9	RASx CASx\ WEx\	Command Input s: RASx, CASx, and Wex\ define t he command being ent ered
G4, G16, K2, K14 M7	DQMLx, DQMHx	Input Data Mask. DM is an input mask signal for write data. Input dat a is masked when DQMLx or Hx is sampled HIGH at t ime of a WRITE access. DM is sampled on bot h edges of DQSLx and DQSHx
E8, E9	BAO, BA1	Bank Address Inputs: BAO, BA1 define which bank an ACTIVE READ, WRITE, or PRECHARGE command is being applied
A7, A8, A9, A10, B7 B8, B9, B10, C7, C8 C9, C10, D7	A0-A11, A12	Address Input: Provide the row address for Active commands, and the column address and autoprecharge bit (A10) for READ/WRITE commands to select one location out of the memory array intithe respective bank. A10 sampled during a PRECHARGE command determines whether the PRECHARGE applies to one bank or all banks. The address inputs also provide the op-code during a MODE RESI ST ER SE T command.

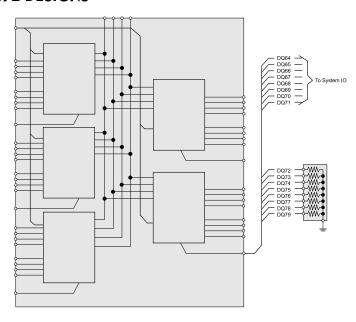
PIN DESCRIPTIONS

BGA LOCATIONS	SYMBOL	DESCRIPTION
A2, A3, A4, A13, A14	DQ0-79	Dat a I/O
B1, B2, B3, B4, B13		
B14, B15, B16, C1,		
C2,C3,C4,C13,C14,		
C15,C16,D1,D2,D3,		
D4,D13,D14,D15,D16		
E1,E16,M1,M16,N1		
N2,N3,N4,N13,N14,		
N15,N16,P1,P2,P3,		
P4,P13,P14,P15,P16		
R1,R2,R3,R4,R13,		
R14,R15,R16,T2,T3,		
T4,T13,T14,T15,N7,		
N8,N9,N10,P7,P8,P9		
P10,R7,R8,R9,R10		
<u>T7,T8,T9,T10</u>		
E6, E7, E10, E11, F5,	DQSLX, DQSHX	Data Strobe: Output with read data, input with write data. DQS is
K5,L12,N5,N12,E5		edge-aligned with read data, centered in write data. It is used to
		capture data.
B11,B12,C5,C6,E3,	VCC	Core Power Supply
F3,G3,H3,H12,H16,		
J3,J12,J16,K3,L3,M3		
P11,P12,R5,R6,T16		
A11,A12,D5,D6,H4,	VCCQ	I/O Power Supply
H15,J4,J15,T5,T6		
A5,A6,A16,B5,B6,	VSS	Ground (Digital)
C11,C12,D11,D12,		
E14,F14,G14,H1,H2,		
H5,H13,H14,J1,J2,J5		
J13,J14,K14,L14		
P5,P6,R11,R12,T1,		
T11,T12, M14		
E12	VREF	SSTL-2 Reference Voltage

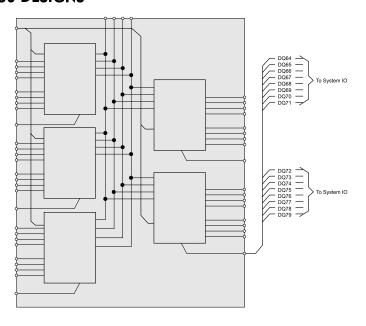




RECOMMENDED IO CONSIDERATION(S) X72 DESIGNS



X80 DESIGNS



MECHANICAL 1.7 0.60

POWER DISSIPATION PROJECTIONS

					MAX			
DESCRIPTIONS	CONDITIONS	SYMBOL	ТУР	7	75	8	UNITS	NOTES
Operating Supply	All inputs Vil or Vih;	IDD	TBD	800	825	775	mA	1
Current	Cycle time tKHKH (min) Outputs open							
Standby Current	tKHKH = tKHKH (min) Device in NOP state All Addresses / Data Static	ISB1	TBD	250	220	190	mA	

Note(s): Power calculated with Outputs unloaded

CAPACITANCE

CONDITIONS	SYM	ТУР	UNITS	NOTES
	Ca	10	рF	
	CI,Co	5	рF	
TA = 25 C; f = 1Mhz				
	Cck	10	рF	
	Ccnt.	5	рF	
		Ca CI,Co TA = 25 C; f = 1Mhz Cck	Ca 10 CI,Co 5 TA = 25 C; f = 1Mhz Cck 10	Ca 10 pF CI,Co 5 pF TA = 25 C; f = 1Mhz Cck 10 pF

Note(s): Power calculated with Outputs unloaded



AC ELECTRICAL CHARACTERISTICS

Parameter		Symbol	7	7	75	75	8	8
Access window of DQs from CLKx / CLKx\		tAC	-0.75	0.75	-0.75	0.75	-0.80	0.80
CLKx high level width		tCH	0.45	0.55	0.45	0.55	0.45	0.55
CLKx low level width	CL=2.5	tCL	0.45	0.55	0.45	0.55	0.45	0.55
Clock Cycle Time	CL = 2	tCK	7.50	13.00	7.50	13.00	8.00	13.00
		tCK	7.50	13.00	10.00	13.00	10.00	13.00
DQ and DM input hold time relative to DQS		tDH	0.50		0.50		0.60	
DQ and DM input setup time relative to DQS		tDS	0.50		0.50		0.60	
DQ and DM input pulse width		tDIPW	1.75		1.75		2.00	
Access window of DQS frm CLKx / CLKx\		tDQSCK	-0.75	0.75	-0.75	0.75	-0.80	0.80
DQS input high pulse width		tDQSH	0.35		0.35		0.35	
DQS input low pulse width		tDQSL	0.35		0.35		0.35	
DQS-DQ skew, DQS to last DQ valid, per group, per	access	tDQSQ		0.50		0.50		0.60
Wrtie command to first DQS latching transition		tDQSS	0.75	1.25	0.75	1.25	0.75	1.25
DQS falling edge to CLKx rising - setup time		tDSS	0.20		0.20		0.20	
DQS falling edge to CLKX rising - hold time		tDSH	0.20		0.20		0.20	
Half clock period		tHP	tCH,tCL		tCH,tCL		tCH,tCL	
Data-out high impedance window from CLK/CLK\		tHZ		0.75		0.75		0.80
Data-out low impedance window from CLK/CLK\		tLZ	-0.75		-0.75		-0.80	
Address and control input hold time		tlH	0.90		0.90		1.10	
Address and control input setup time		tIS	1.00		1.00		1.10	
Load Mode Register		tMRD	15.00		15.00		16.00	
DQ-DQS hold, DQS to first DQ to go non-valid		tQH	tHP - tQHS		tHP - tQHS		tHP - tQHS	
Data hold skew factor		tQHS		0.75		0.75		1.00
ACTIVE to PRECHARGE command		tRAS	40.00	120K	40.00	120K	40.00	120K
ACTIVE to READ with AUTO PRECHARGE command		tRAP			tRAS (min) - (burst length x tC		x tCLK/e)	
ACTIVE to ACTIVE/AUTO REFRESH command period		tRC	65.00		65.00		70.00	
AUTO REFRESH command period		tRFC	75.00		75.00		80.00	
ACTIVE to READ or WRITE		tRCD	20.00		20.00		20.00	
PRECHARGE command period		tRP	20.00		20.00		20.00	
DQS read preamble		tRPRE	0.90	1.10	0.90	1.10	0.90	1.10
DQS read postamble		tRPST	0.40	0.60	0.40	0.60	0.40	0.60
ACTIVE bank to ACTIVE bank b command		tRRD	15.00		15.00		15.00	
DQS write preamble		tWPRE	0.25		0.25		0.25	
DQS write preamble setup time		tWPRES	0.00		0.00		0.00	
Half clock period		tWPST	0.40	0.60	0.40	0.60	0.40	0.60
Data-out high impedance window from CLK/CLK\		tWR	15.00		15.00		15.00	
Data-out low impedance window from CLK/CLK\		tREFC		140.60		140.60		140.60
Address and control input hold time		tXSNR	75.00		75.00		80.00	
Address and control input setup time		tXSRD	200.00		200.00		200.00	

ORDERING INFORMATION

PART NUMBER	CONFIGURATION	TECHNOLOGY	FREQUENCY	VCC	TEMP
WED3EL7216S7ES	16M x 72	SDRAM; DDR	133/266 Mhz	2.5	ENG. SAMPLES
WED3EL7216S75ES	16M x 72	SDRAM; DDR	133/266 Mhz	2.5	ENG. SAMPLES
WED3EL7216S8ES	16M x 72	SDRAM; DDR	100/200 Mhz	2.5	ENG. SAMPLES
WED3EL7216S7BC	16M x 72	SDRAM; DDR	133/266 Mhz	2.5	0C - 70C
WED3EL7216S75BC	16M x 72	SDRAM; DDR	133/266 Mhz	2.5	0C - 70C
WED3EL7216S8BC	16M x 72	SDRAM; DDR	100/200 Mhz	2.5	0C - 70C